

DMN3022LDG

30V SYNCHRONOUS N-CHANNEL ENHANCEMENT MODE MOSFET PowerDI3333-8 (Type D)

Product Summary

Device	BV _{DSS}	R _{DS(ON)} Max
Q1	30V	$22m\Omega$ @ $V_{GS} = 5V$, $I_D = 10A$
Q2	30V	$8m\Omega @ V_{GS} = 5V, I_D = 10A$

Features and Benefits

- 100% Unclamped Inductive Switch (UIS) Test in Production
- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Lead-Free Finish; RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

Description and Applications

This new generation MOSFET is designed to minimize the on-state resistance (R_{DS(ON)}) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- DC-DC Converters
- Power Management Functions
- Analog Switch

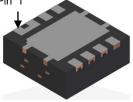
Mechanical Data

- Case: PowerDI[®]3333-8 (Type D)
- Case Material: Molded Plastic, "Green" Molding Compound.
 UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Matte Tin Annealed over Copper Leadframe.
 Solderable per MIL-STD-202, Method 208 ⁽³⁾
- Weight: 0.044 grams (Approximate)

Pin 1

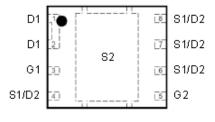
PowerDI3333-8 (Type D)





Top View

Bottom View



Top View Pin Configuration

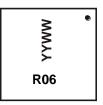
Ordering Information (Note 4)

Part Number	Case	Packaging
DMN3022LDG-7	PowerDI3333-8 (Type D)	1,000/Tape & Reel
DMN3022LDG-13	PowerDI3333-8 (Type D)	3,000/Tape & Reel

Notes:

- 1. EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant. All applicable RoHS exemptions applied.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at https://www.diodes.com/design/support/packaging/diodes-packaging/

Marking Information



R06 = Product Type Marking Code YYWW = Date Code Marking YY = Last Two Digits of Year (ex: 18 = 2018) WW = Week Code (01 to 53)

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Maximum Ratings (@ $T_A = +25^{\circ}C$, unless otherwise specified.)

Characteristic	Symbol	Q1	Q2	Unit	
Drain-Source Voltage		V_{DSS}	30		V
Gate-Source Voltage	V _{GSS}	±10		V	
Continuous Prais Correct @ V 5V	$T_C = +25$ °C $T_C = +70$ °C	I _D	15 12		А
Continuous Drain Current @ V _{GS} = 5V	T _A = +25°C T _A = +70°C	I _D	7.6 6.1		А
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)		I _{DM}	50	100	Α
Avalanche Current (Note 6) L = 0.1mH		I _{AS}	24	43	Α
Avalanche Energy (Note 6) L = 0.1mH		Eas	28	92	mJ

Thermal Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Unit	
Total Power Dissipation	$T_A = +25^{\circ}C$	ס	1.96	W	
Total Fower Dissipation	$T_A = +70^{\circ}C$	P_{D}	1.25	VV	
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	ם	64	°C/W	
mermai Resistance, Junction to Ambient (Note 5)	t < 10s	$R_{\theta JA}$	36		
Thermal Resistance, Junction to Case (Note 5)		$R_{\theta JC}$	8.7		
Operating and Storage Temperature Range		T _{J,} T _{STG}	-55 to +150	°C	

Electrical Characteristics Q1 (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1	μΑ	$V_{DS} = 20V, V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 10V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V _{GS(TH)}	1	1.4	2.1	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Static Drain-Source On-Resistance	R _{DS(ON)}	_	16	22	mΩ	$V_{GS} = 5V, I_D = 10A$
Forward Transfer Admittance	Y _{FS}	_	17	_	S	$V_{DS} = 5V, I_{D} = 8A$
Diode Forward Voltage	V _{SD}	_	0.84	1	V	$V_{GS} = 0V, I_{S} = 8A$
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C _{iss}	_	370	481	pF	V _{DS} = 15V, V _{GS} = 0V, f = 1.0MHz
Output Capacitance	Coss	_	176	228		
Reverse Transfer Capacitance	C _{rss}	_	8.2	10.6		
Gate Resistance	R _G	_	2.5	6.5	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$
Total Gate Charge (V _{GS} = 4.5V)	Q _G	_	2.8	3.7		V _{DS} = 15V, I _D = 8A
Total Gate Charge at V _{TH}	Q _{G(TH)}	_	0.35	_	nC	
Gate-Source Charge	Q _{GS}	_	0.6	_	lic	
Gate-Drain Charge	Q_{GD}	_	0.5	_		
Turn-On Delay Time	t _{D(ON)}	_	4.5	6.7		$V_{DD} = 15V, V_{GS} = 4.5V,$ $I_{D} = 8A, R_{G} = 2\Omega$
Turn-On Rise Time	t _R	_	1.8	_		
Turn-Off Delay Time	t _{D(OFF)}	_	7.2	10.8	ns	
Turn-Off Fall Time	t _F	_	1.9	_		
Reverse Recovery Time	t _{RR}	_	11.5	_	ns	
Reverse Recovery Charge	Q _{RR}	_	6.9	_	nC	$I_F = 8A$, di/dt = 300A/ μ s

Notes

- 5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
- 6. I_{AS} and E_{AS} ratings are based on low frequency and duty cycles to keep T_J = +25°C.
- 7. Short duration pulse test used to minimize self-heating effect.
- 8. Guaranteed by design. Not subject to product testing.

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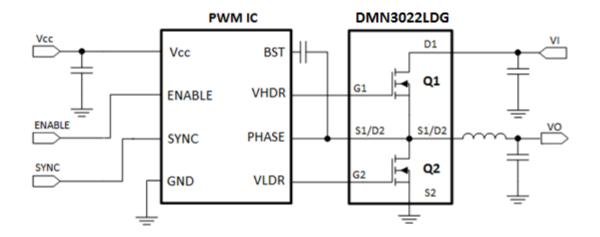


Electrical Characteristics Q2 (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current T _J = +25°C	I _{DSS}	_	_	1.0	μA	$V_{DS} = 20V$, $V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 10V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	$V_{GS(TH)}$	0.8	0.96	1.2	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance	R _{DS(ON)}	_	6.4	8	mΩ	$V_{GS} = 5V, I_D = 10A$	
Forward Transfer Admittance	Y _{FS}	_	33	_	S	$V_{DS} = 5V, I_{D} = 8A$	
Diode Forward Voltage	V_{SD}	_	0.78	1	V	$V_{GS} = 0V, I_{S} = 8A$	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C _{iss}	_	766	996	pF	V _{DS} = 15V, V _{GS} = 0V, f = 1.0MHz	
Output Capacitance	Coss	_	441	573	pF		
Reverse Transfer Capacitance	C_{rss}	_	19	25	pF	1 = 1.000112	
Gate Resistance	R_{G}	_	0.69	1.5	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge (V _{GS} = 4.5V)	Q_{G}	_	6.1	8	nC		
Total Gate Charge at V _{TH}	Q _{G(TH)}	_	0.47	_	nC	151/ 1 00	
Gate-Source Charge	Q _{GS}	_	0.8	_	nC	$V_{DS} = 15V, I_{D} = 8A$	
Gate-Drain Charge	Q_{GD}	_	1.1	_	nC		
Turn-On Delay Time	t _{D(ON)}	_	5.6	8.4	ns	$V_{DD} = 15V, V_{GS} = 4.5V,$ $I_{D} = 8A, R_{G} = 2\Omega$	
Turn-On Rise Time	t _R	_	2.5	_	ns		
Turn-Off Delay Time	t _{D(OFF)}	_	11.7	17.5	ns		
Turn-Off Fall Time	t _F		2.4		ns		
Reverse Recovery Time	t _{RR}	_	27.9	_	ns	1 9A di/dt 200A/us	
Reverse Recovery Charge	Q_{RR}		9.9		nC	$I_F = 8A$, di/dt = 300A/ μ s	

7. Short duration pulse test used to minimize self-heating effect. 8. Guaranteed by design. Not subject to product testing. Notes:

Typical Circuit





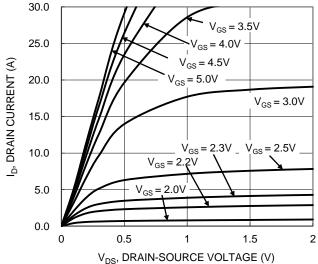
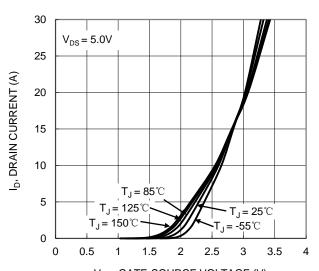


Figure 1. Q1 Typical Output Characteristic



 V_{GS} , GATE-SOURCE VOLTAGE (V) Figure 3. Q1 Typical Transfer Characteristic

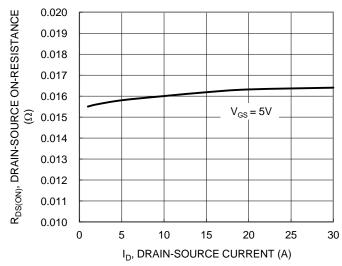
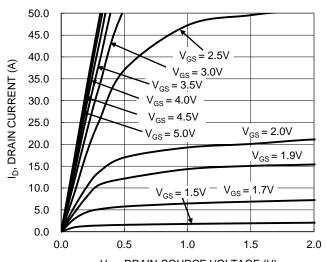


Figure 5. Q1 Typical On-Resistance vs. Drain Current and Gate Voltage



 $\rm V_{DS}, \, DRAIN\text{-}SOURCE \, VOLTAGE \, (V)$ Figure 2. Q2 Typical Output Characteristic

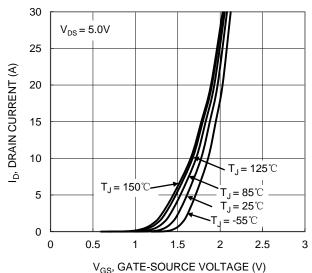


Figure 4. Q2 Typical Transfer Characteristic

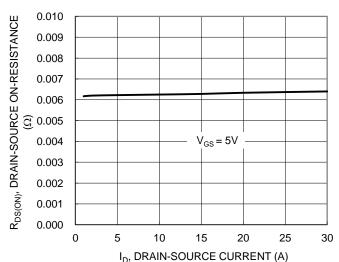
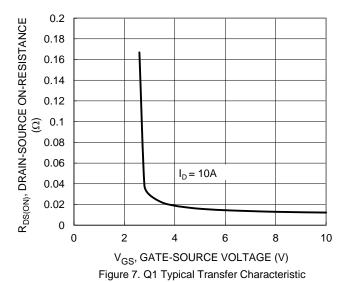
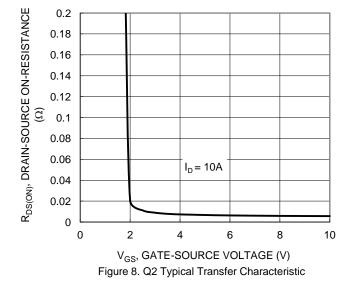
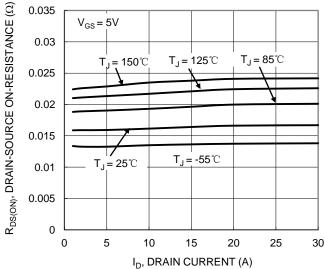


Figure 6. Q2 Typical On-Resistance vs. Drain Current and Gate Voltage









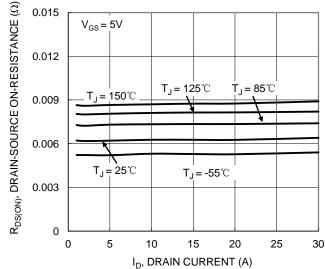
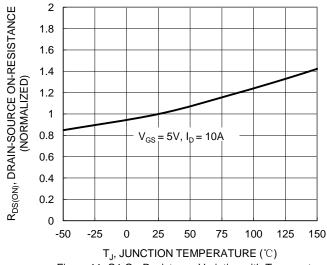


Figure 9. Q1 Typical On-Resistance vs. Drain Current and Temperature

Figure 10. Q2 Typical On-Resistance vs. Drain Current and Temperature



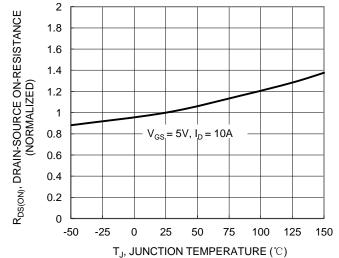


Figure 11. Q1 On-Resistance Variation with Temperature

Figure 12. Q2 On-Resistance Variation with Temperature



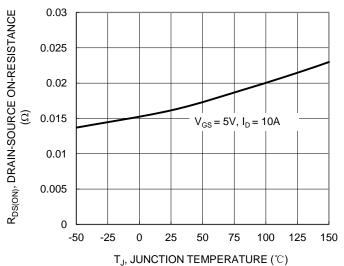


Figure 13. Q1 On-Resistance Variation with Temperature

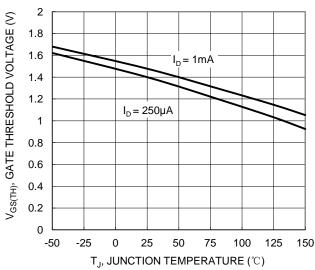
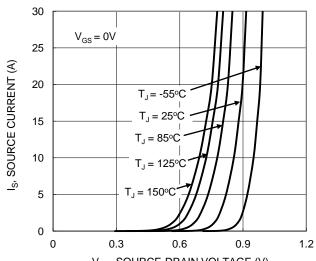


Figure 15. Q1 Gate Threshold Variation vs. Junction Temperature



V_{SD}, SOURCE-DRAIN VOLTAGE (V) Figure 17. Q1 Diode Forward Voltage vs. Current

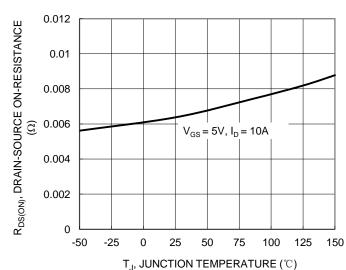


Figure 14. Q2 On-Resistance Variation with Temperature

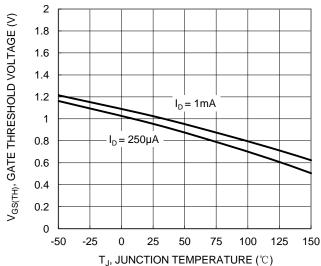


Figure 16. Q2 Gate Threshold Variation vs. Junction Temperature

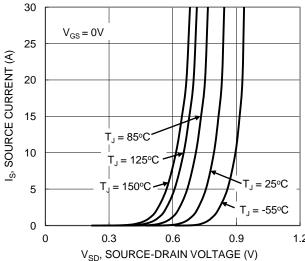


Figure 18. Q2 Diode Forward Voltage vs. Current



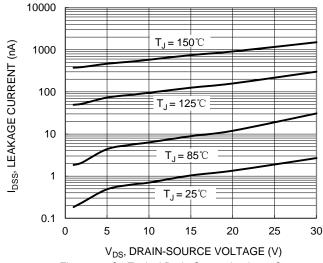


Figure 19. Q1 Typical Drain-Source Leakage Current vs.
Voltage

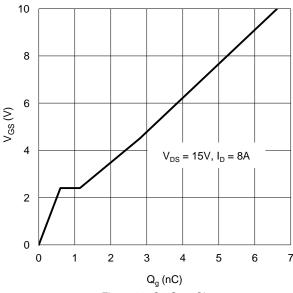


Figure 21. Q1 Gate Charge

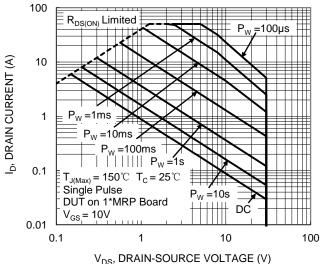


Figure 23. Q1 SOA, Safe Operation Area

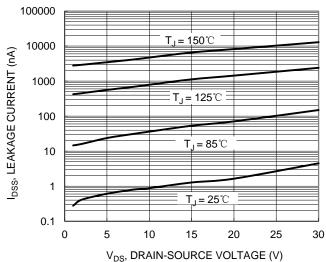


Figure 20. Q2 Typical Drain-Source Leakage Current vs.

Voltage

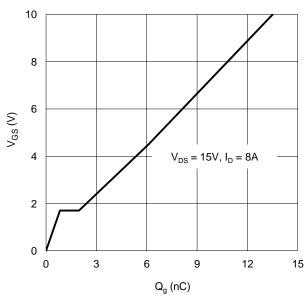


Figure 22. Q2 Gate Charge

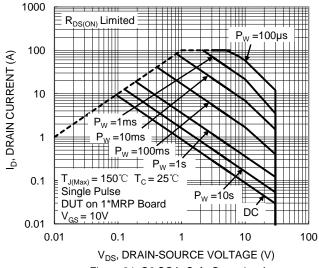


Figure 24. Q2 SOA, Safe Operation Area



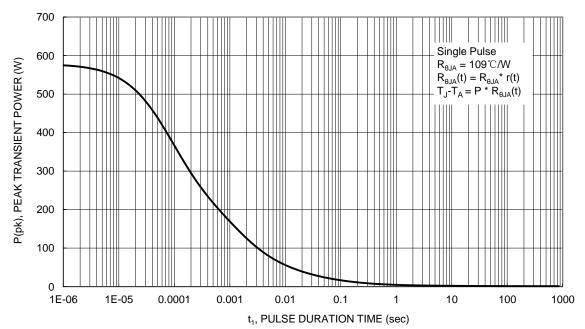


Figure 25. Single Pulse Maximum Power Dissipation

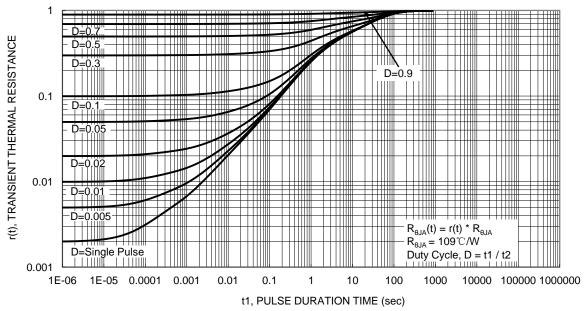


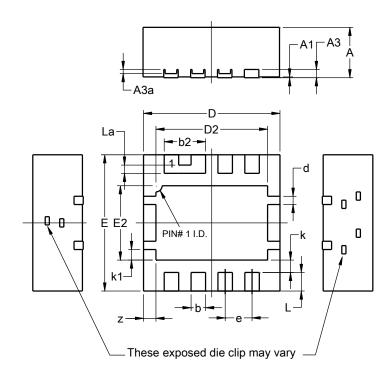
Figure 26. Transient Thermal Resistance



Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

PowerDI3333-8 (Type D)

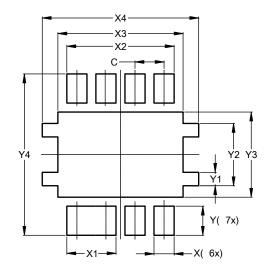


	PowerDI3333-8						
	(Type D)						
Dim	Min	Min Max Typ					
Α	1.17	1.23	1.20				
A1	0.00	0.05	0.02				
A3	0.15	0.25	0.20				
A3a	0.05	0.15	0.10				
b	0.30	0.40	0.35				
b2	0.95	1.05	1.00				
D	3.20	3.40	3.30				
D2	2.65	2.75	2.70				
Е	3.20	3.40	3.30				
E2	1.75	1.85	1.80				
d	0.15	0.25	0.20				
е			0.65				
k			0.30				
k1	0.21	0.31	0.26				
L	0.40	0.50	0.45				
La	0.15	0.25	0.20				
Z	0.25	0.35	0.30				
All Dimensions in mm							

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

PowerDI3333-8 (Type D)



Dimensions	Value			
Dilliensions	(in mm)			
С	0.650			
X	0.450			
X1	1.100			
X2	2.400			
Х3	2.800			
X4	3.500			
Y	0.650			
Y1	0.300			
Y2	1.390			
Y3	1.900			
Y4	3.600			



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